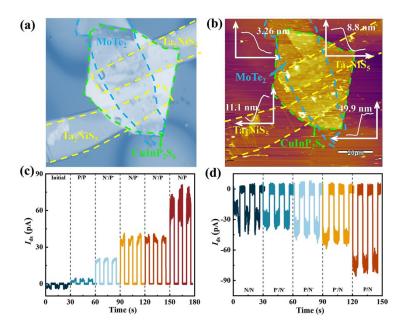
Supplementary Information (SI) for Journal of Materials Chemistry C. This journal is © The Royal Society of Chemistry 2024

## **Supporting Information**

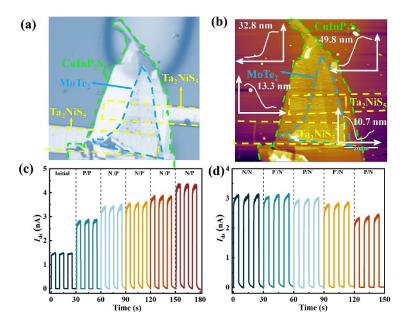
Ferroelectric polarization-modulated two-dimensional homojunctions for enhanced nonvolatile multistate memory with self-powered optical readout capacity

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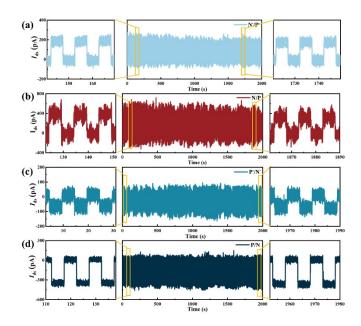
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**Figure S1.** (a)The optical image. (b) The AFM image show the device with a thickness of 3.26 nm for MoTe<sub>2</sub>. The insets show the thickness of MoTe<sub>2</sub>, CuInP<sub>2</sub>S<sub>6</sub> and Ta<sub>2</sub>NiS<sub>5</sub> nanoflakes, respectively. (c, d) the *I*-t characteristics under different states. All measurements were performed at 660 nm, an intensity of 7.96 mW/cm<sup>2</sup> and zero bias.



**Figure S2.** (a)The optical image. (b)The AFM image show the device with a thickness of 32.8 nm for MoTe<sub>2</sub>. The insets show the thickness of MoTe<sub>2</sub>, CuInP<sub>2</sub>S<sub>6</sub> and Ta<sub>2</sub>NiS<sub>5</sub> nanoflakes, respectively. (c, d) the *I*-t characteristics under different states. All measurements were performed at 660 nm, an intensity of 7.96 mW/cm<sup>2</sup> and zero bias.



**Figure S3.** Retention performance of device in four different states, namely N<sup>-</sup>/P<sup>-</sup> (a), N/P (b), P<sup>-</sup>/N<sup>-</sup> (c), and P/N(d). All measurements were performed at 660 nm, intensity of 7.96 mW/cm<sup>2</sup> and zero bias.